



# SHENZHEN TUOFENG SEMICONDUCTOR TECHNOLOGY CO.,LTD

## N-Channel Enhancement Mode Power MOSFET

TUO FENG

**6764**

### 30V N-Channel MOSFET

#### General Features

$V_{DS}$  30V  
 $I_D$  (at  $V_{GS}=10V$ ) 85A  
 $R_{DS(ON)}$  (at  $V_{GS}=10V$ ) < 4.00mΩ  
 $R_{DS(ON)}$  (at  $V_{GS}=4.5V$ ) < 5.00mΩ

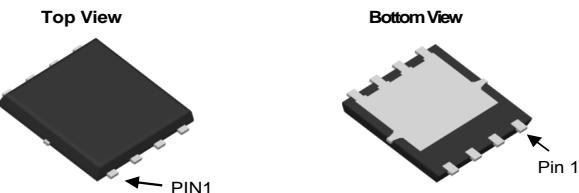
100% UIS Tested  
100%  $R_g$  Tested

- Trench Power αMOS Technology
- Low  $R_{DS(ON)}$
- Low Gate Charge
- High Current Capability
- RoHS and Halogen-Free Compliant

#### Applications

- DC/DC Converters in Computing
- Isolated DC/DC Converters in Telecom and Industrial

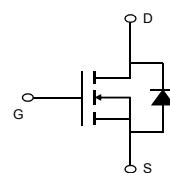
#### PDFN5X6-8L



#### Top View



#### Equivalent Circuit



Y :year code W :week code

Orderable Part Number	Package Type		Form	Minimum Order Quantity
6764	DFN 5x6		Tape&Reel	3000
<b>Absolute Maximum Ratings <math>T_A=25^\circ C</math> unless otherwise noted</b>				
Parameter	Symbol	Maximum	Units	
Drain-Source Voltage	$V_{DS}$	30	V	
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V	
Continuous Drain Current <sup>G</sup> $T_c=25^\circ C$	$I_D$	85	A	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	190		
Continuous Drain Current	$I_{DSM}$	37	A	
Avalanche Current <sup>C</sup>	$I_{AS}$	42	A	
Avalanche energy $L=0.05mH$ <sup>C</sup>	$E_{AS}$	44	mJ	
$V_{DS}$ Spike	10μs	$V_{SPIKE}$	36	V
Power Dissipation <sup>B</sup>	$T_c=25^\circ C$	$P_D$	42	W
Power Dissipation <sup>A</sup>	$T_A=25^\circ C$	$P_{DSM}$	6.2	W
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C	
<b>Thermal Characteristics</b>				
Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup> $t \leq 10s$	$R_{\theta JA}$	15	20	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup> Steady-State		40	50	°C/W
Maximum Junction-to-Case Steady-State	$R_{\theta JC}$	2.4	3	°C/W



SHENZHEN TUOFENG SEMICONDUCTOR TECHNOLOGY CO.,LTD  
N-Channel Enhancement Mode Power MOSFET

6764

Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$\text{ID}=10\text{mA}, \text{VGS}=0\text{V}$	30			V
$\text{I}_{\text{DSS}}$	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=30\text{V}, \text{V}_{\text{GS}}=0\text{V}$			0.5	uA
$\text{I}_{\text{GSS}}$	Gate-Body leakage current	$\text{V}_{\text{DS}}=0\text{V}, \text{V}_{\text{GS}}=\pm 12\text{V}$			$\pm 100$	nA
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_{\text{D}}=250\mu\text{A}$	1.1	1.5	1.9	V
$\text{R}_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{D}}=20\text{A}$		3.8	4.0	mΩ
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_{\text{D}}=20\text{A}$		4.5	5.0	mΩ
$\text{g}_{\text{FS}}$	Forward Transconductance	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_{\text{D}}=20\text{A}$		167		S
$\text{V}_{\text{SD}}$	Diode Forward Voltage	$\text{I}_{\text{S}}=1\text{A}, \text{V}_{\text{GS}}=0\text{V}$		0.5	0.7	V
$\text{I}_{\text{S}}$	Maximum Body-Diode Continuous Current				30	A
<b>DYNAMIC PARAMETERS</b>						
$\text{C}_{\text{iss}}$	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{f}=1\text{MHz}$		2120		pF
$\text{C}_{\text{oss}}$	Output Capacitance			700		pF
$\text{C}_{\text{rss}}$	Reverse Transfer Capacitance			69		pF
$\text{R}_{\text{g}}$	Gate resistance	f=1MHz	0.9	1.8	2.7	Ω
<b>SWITCHING PARAMETERS</b>						
$\text{Q}_{\text{g}}(10\text{V})$	Total Gate Charge	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{I}_{\text{D}}=20\text{A}$		37		nC
$\text{Q}_{\text{g}}(4.5\text{V})$	Total Gate Charge			16.8		nC
$\text{Q}_{\text{gs}}$	Gate Source Charge			5		nC
$\text{Q}_{\text{gd}}$	Gate Drain Charge			4.9		nC
$\text{t}_{\text{D(on)}}$	Turn-On Delay Time	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{R}_{\text{L}}=0.75\Omega, \text{R}_{\text{GEN}}=3\Omega$		7		ns
$\text{t}_{\text{r}}$	Turn-On Rise Time			3.5		ns
$\text{t}_{\text{D(off)}}$	Turn-Off Delay Time			36		ns
$\text{t}_{\text{f}}$	Turn-Off Fall Time			6		ns
$\text{t}_{\text{rr}}$	Body Diode Reverse Recovery Time	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		15.5		ns
$\text{Q}_{\text{rr}}$	Body Diode Reverse Recovery Charge	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		33		nC

A. The value of  $R_{\text{DSM}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The Power dissipation  $P_{\text{DSM}}$  is based on  $R_{\text{DSM}} \leq 10\text{s}$  and the maximum allowed junction temperature of  $150^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ .

D. The  $R_{\text{WA}}$  is the sum of the thermal impedance from junction to case  $R_{\text{JJC}}$  and case to ambient.

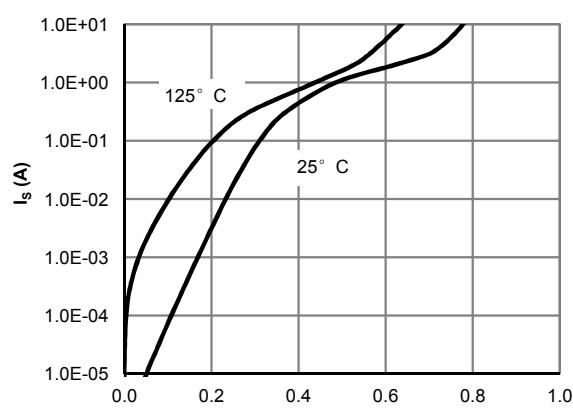
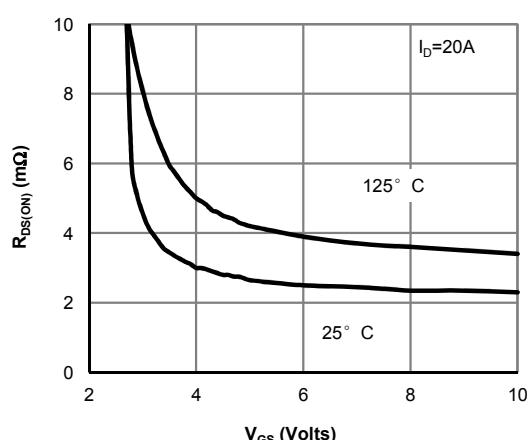
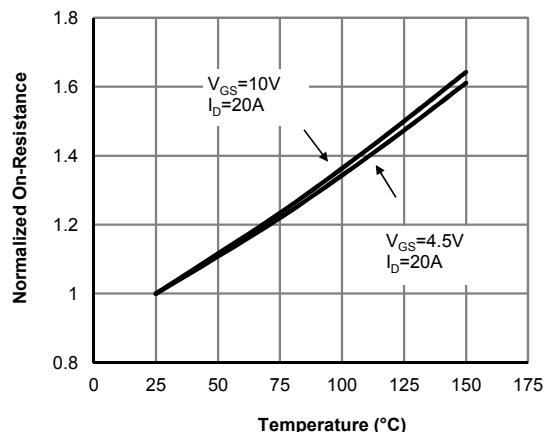
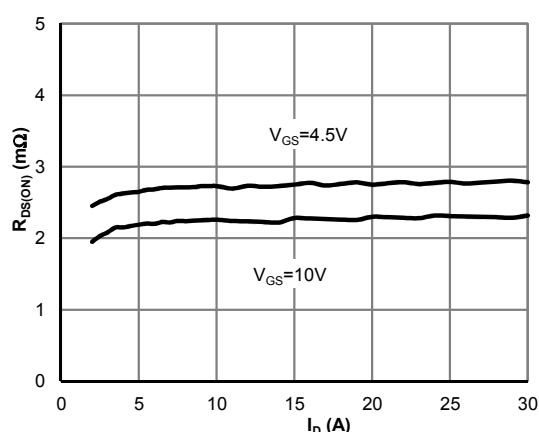
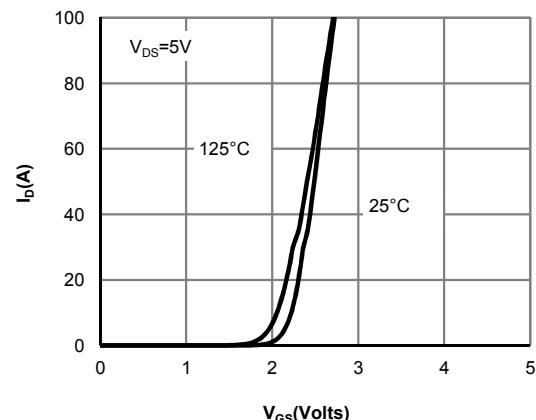
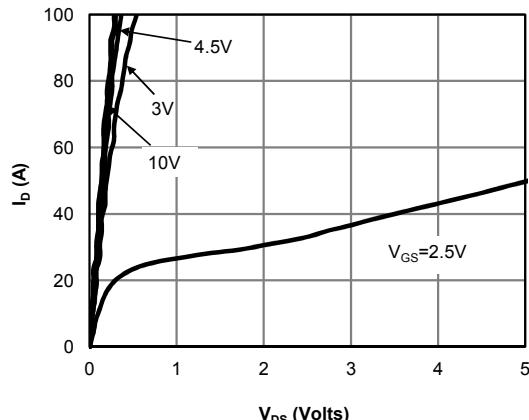
E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ .

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**





# SHENZHEN TUOFENG SEMICONDUCTOR TECHNOLOGY CO.,LTD

## N-Channel Enhancement Mode Power MOSFET

**6764**

### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

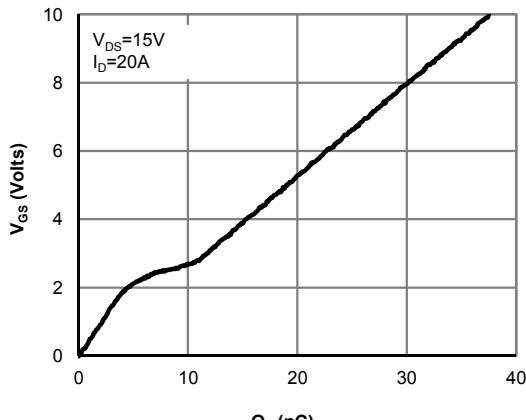


Figure 7: Gate-Charge Characteristics

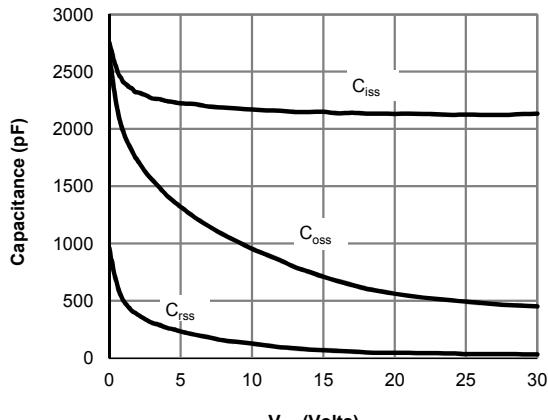


Figure 8: Capacitance Characteristics

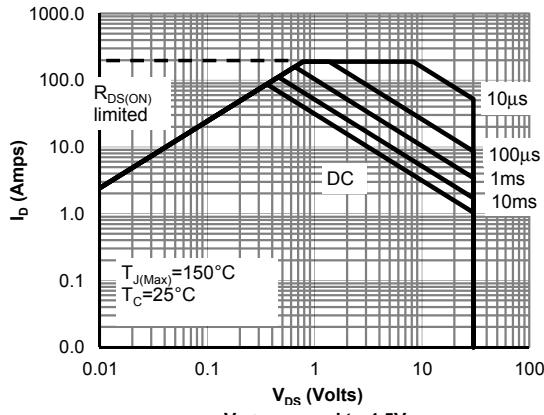


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

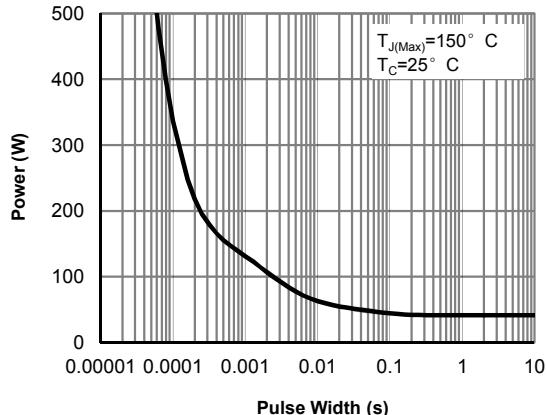


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

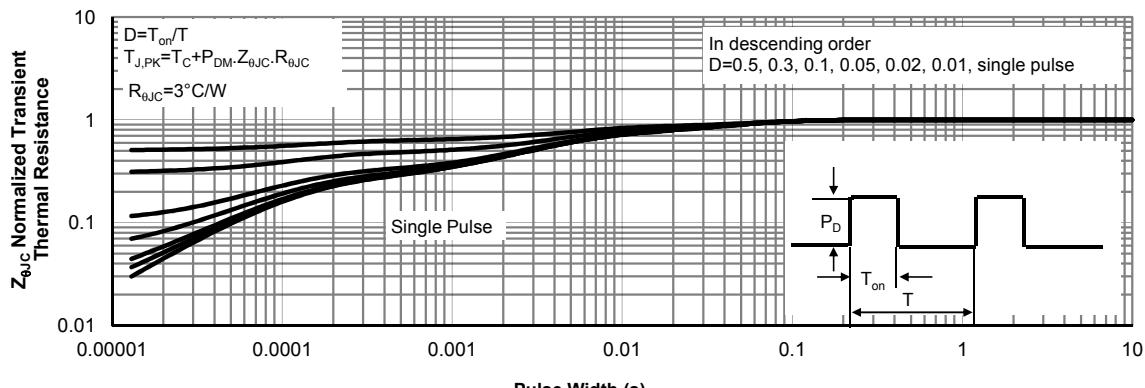


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



SHENZHEN TUOFENG SEMICONDUCTOR TECHNOLOGY CO.,LTD

N-Channel Enhancement Mode Power MOSFET

6764

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

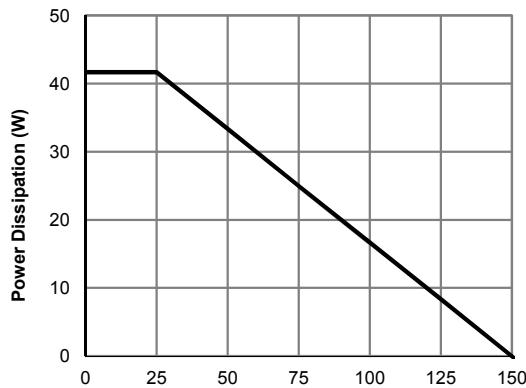


Figure 12: Power De-rating (Note F)

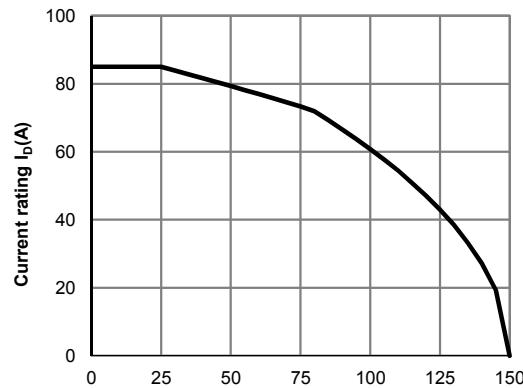


Figure 13: Current De-rating (Note F)

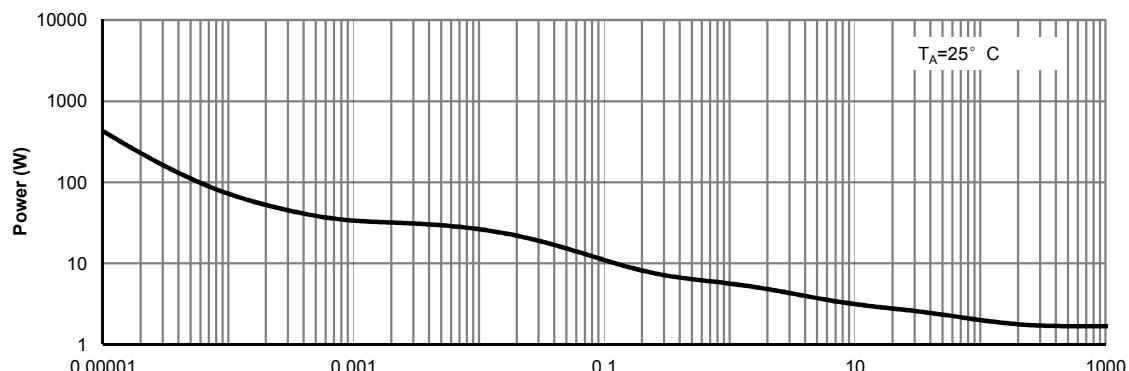


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

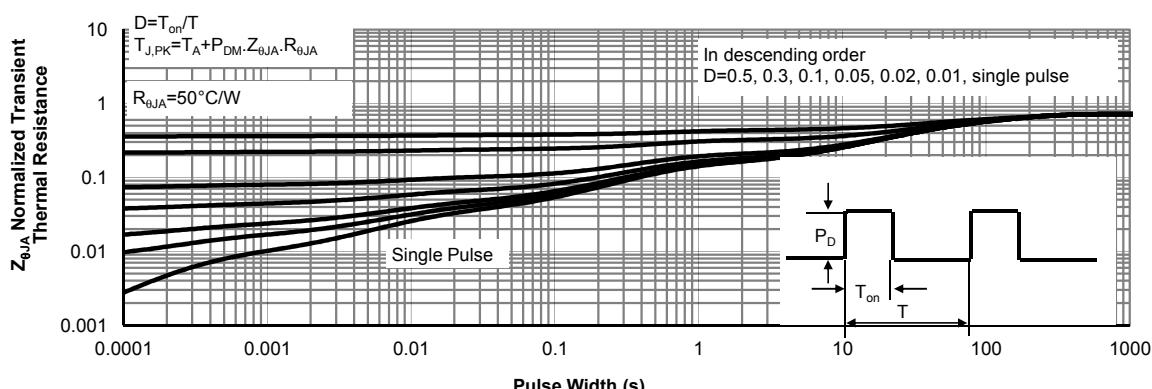
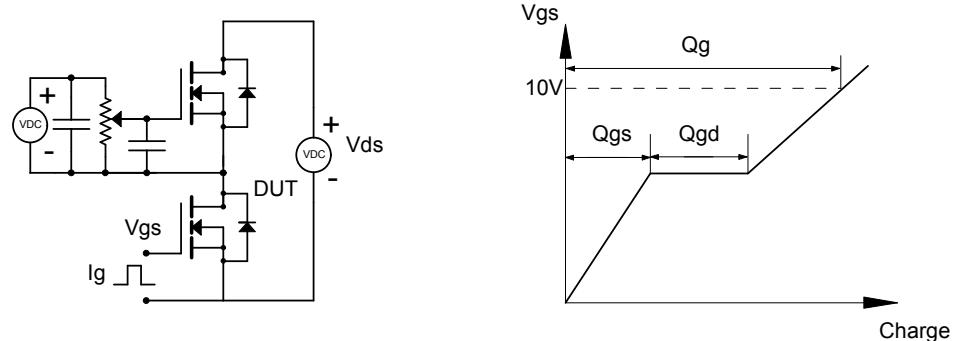
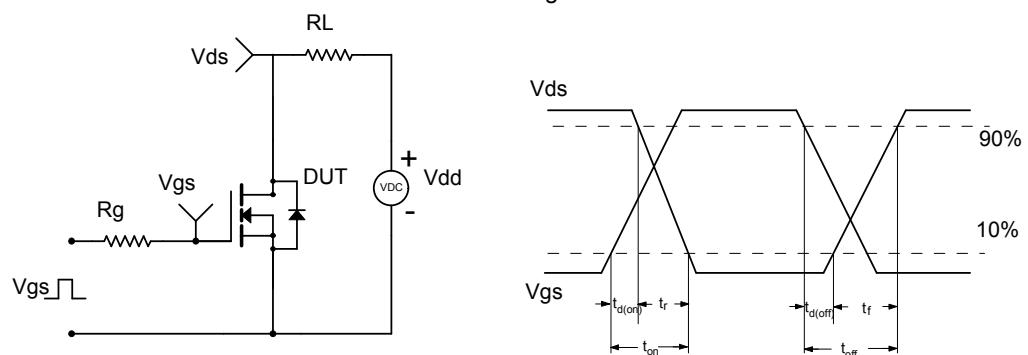


Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

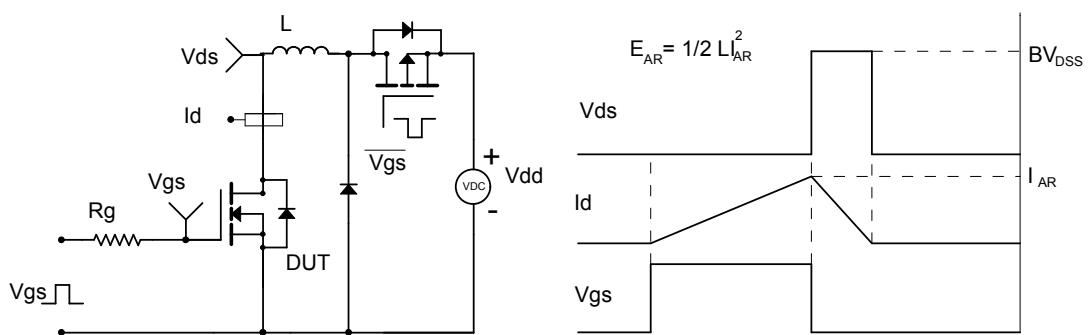
Gate Charge Test Circuit & Waveform



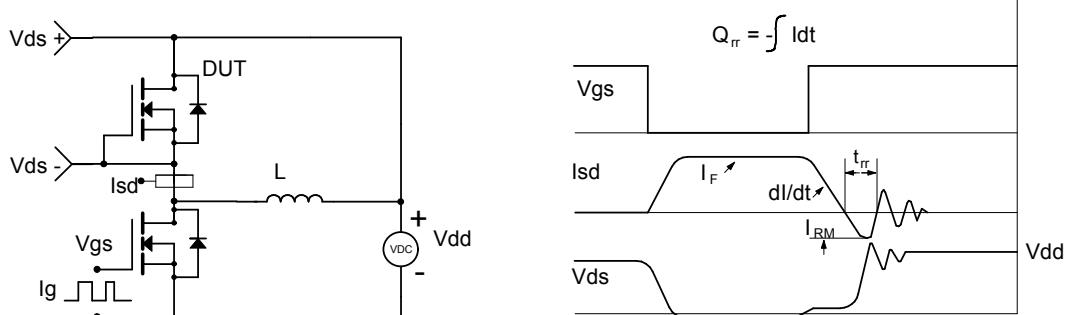
Resistive Switching Test Circuit & Waveforms



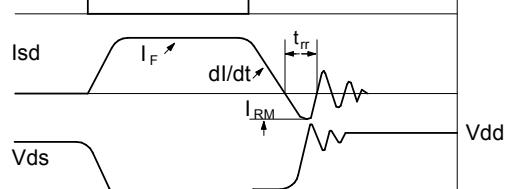
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

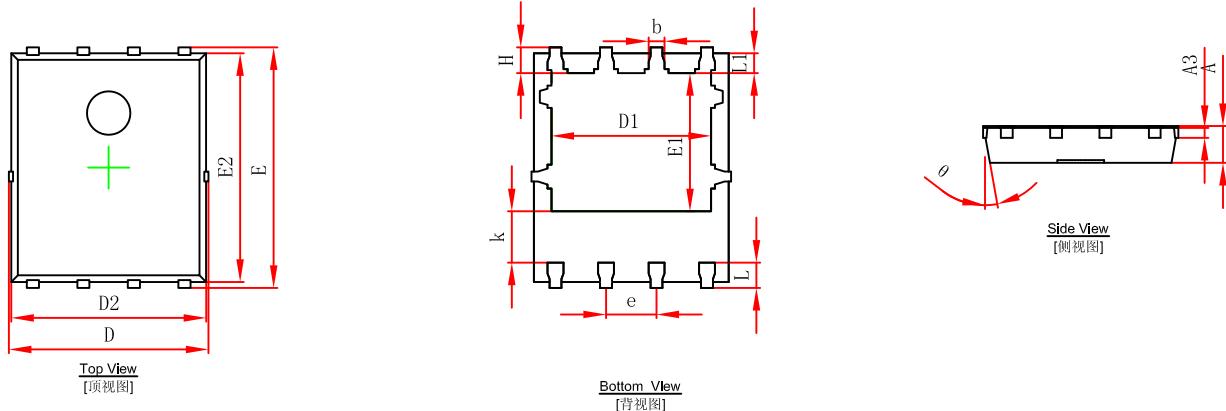


$$Q_{rr} = \int I dt$$



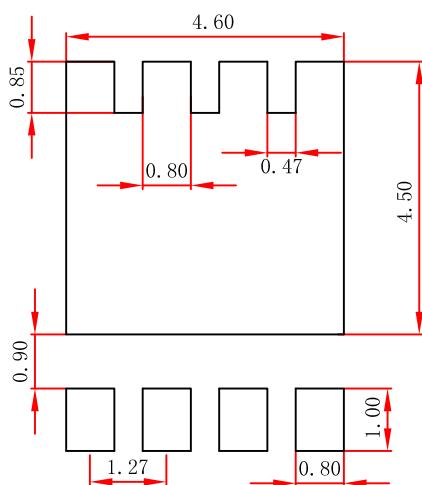


### PDFNWB5x6-8L Package Outline Dimensions



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039
A3	0.254REF.		0.010REF.	
D	4.944	5.096	0.195	0.201
E	5.974	6.126	0.235	0.241
D1	3.910	4.110	0.154	0.162
E1	3.375	3.575	0.133	0.141
D2	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.390	0.047	0.055
b	0.350	0.450	0.014	0.018
e	1.270TYP.		0.050TYP.	
L	0.559	0.711	0.022	0.028
L1	0.424	0.576	0.017	0.023
H	0.574	0.726	0.023	0.029
theta	10°	12°	10°	12°

### PDFNWB5x6-8L Suggested Pad Layout



#### Note:

1. Controlling dimension:in millimeters.
2. General tolerance: $\pm 0.05\text{mm}$ .
3. The pad layout is for reference purposes only.